Supertex inc.

Pre-Release Information



Ordering Information

BV _{DSS} /	R _{DS(ON)}	V _{GS(th)}	I _{D(ON)}	Order Number / Package	
BV _{DGS}	(max)	(max)	(min)	TO-243AA*	
-240V	8.0Ω	-2.4V	-800mA	TP2424N8	

^{*} Same as SOT-89. Product supplied on 2000 piece carrier tape reels.

Features

	Low threshold
	High input impedance
	Low input capacitance
	Fast switching speeds
	Free from secondary breakdown
	Low input and output leakage
٦	Complementary N- and P-channel devices

Applications

	Logic level interfaces – ideal for TTL and CMOS
	Solid state relays
	Linear Amplifiers
	Power Management
	Analog switches
П	Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV _{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

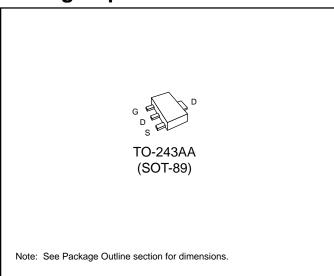
^{*} Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options



06/09/99

Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)	Power Dissipation	Power Dissipation $ heta_{ m jc}$		I _{DR} *	I _{DRM}
			@ T _A = 25°C	°C/W	°C/W		
TO-243AA	-316mA	-1.9A	1.6W [†]	15	78 [†]	-316mA	-1.9A

Electrical Characteristics (@ 25°C unless otherwise specified)

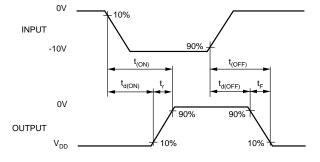
Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	-240			V	$V_{GS} = 0V, I_D = -250\mu A$	
V _{GS(th)}	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}$, $I_D = -1.0$ mA	
$\Delta V_{GS(th)}$	Change in V _{GS(th)} with Temperature			4.5	mV/°C	$V_{GS} = V_{DS}$, $I_D = -1.0$ mA	
I _{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
I _{DSS}	Zero Gate Voltage Drain Current			-10.0	μΑ	V _{GS} = 0V, V _{DS} = Max Rating	
				-1.0	mA	$V_{GS} = 0V$, $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C	
I _{D(ON)}	ON-State Drain Current	-0.3			Α	$V_{GS} = -4.5V, V_{DS} = -25V$	
		-0.8				V _{GS} = -10V, V _{DS} = -25V	
R _{DS(ON)}	Static Drain-to-Source			10.0	Ω	$V_{GS} = -4.5V, I_{D} = -150mA$	
	ON-State Resistance			8.0		V _{GS} = -10V, I _D = -500mA	
$\Delta R_{DS(ON)}$	Change in R _{DS(ON)} with Temperature			0.75	%/°C	$V_{GS} = -10V, I_{D} = -500 \text{mA}$	
G _{FS}	Forward Transconductance	150			m℧	$V_{DS} = -25V, I_{D} = -200mA$	
C _{ISS}	Input Capacitance			200		$V_{GS} = 0V, V_{DS} = -25V$	
C _{OSS}	Common Source Output Capacitance			100	pF	$v_{GS} = 0v, v_{DS} = -25v$ f = 1.0 MHz	
C_{RSS}	Reverse Transfer Capacitance			40			
t _{d(ON)}	Turn-ON Delay Time			20)	
t _r	Rise Time			30	ns	$V_{DD} = -25V,$ $I_{D} = -250\text{mA},$ $R_{GEN} = 25\Omega$	
t _{d(OFF)}	Turn-OFF Delay Time			35			
t _f	Fall Time			25			
V _{SD}	Diode Forward Voltage Drop			-1.5	V	$V_{GS} = 0V, I_{SD} = -500 \text{mA}$	
t _{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0V, I_{SD} = -500 \text{mA}$	

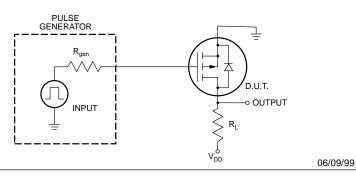
Notes:

1.All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)

2.All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





 $^{^{\}dagger}$ Mounted on FR5 board, 25mm x 25mm x 1.57mm. Significant $P_{\scriptscriptstyle D}$ increase possible on ceramic substrate.